Special use of correctors for uncommon experiments: free electron orbital angular momentum and beyond

Peng-Han Lu | 31 August 2025

Ernst Ruska-Centre for Microscopy and Spectroscopy with Electrons, Research Centre Juelich, Juelich, Germany

With contributions from

Vienna: Thomas Schachinger, Stefan Löffler, and Peter Schattschneider

Modena: Vincenzo Grillo and his co-workers Heidelberg: Peter Hartel and Martin Linck

Berlin: Tolga Wagner

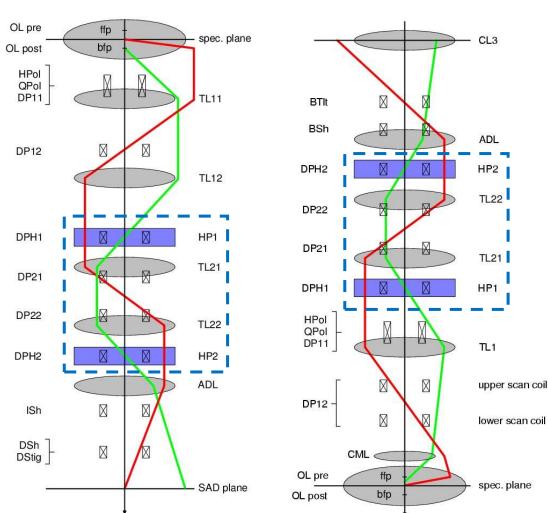
Juelich: Amir Tavabi and Rafal E. Dunin-Borkowski



Cs corrector as an electron optical bench

CETCOR - CTEM

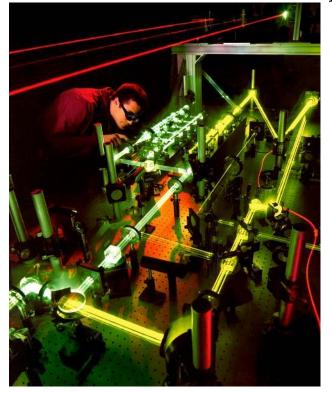
CESCOR - STEM



https://www.ceos-gmbh.de/en/produkte/residualsCEXCOR

Not only double hexapole for aberration correction, but also additional deflectors, dipoles, quadrupoles, hexapoles and transfer lenses for alignment and correcting parasitic aberrations.

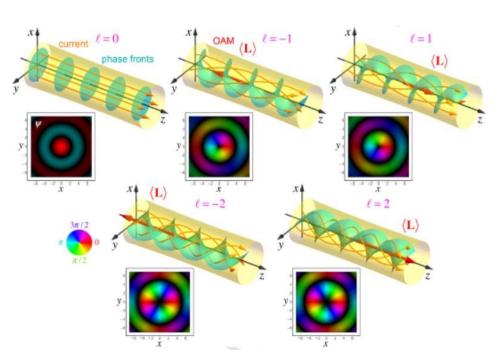
We could also treat it as an electron optical bench!



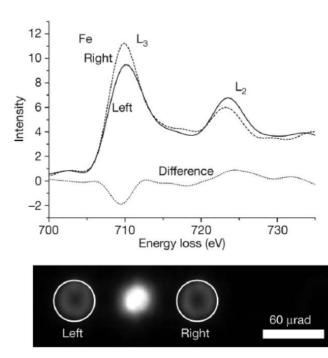
https://www.needpix.com/photo/47763/



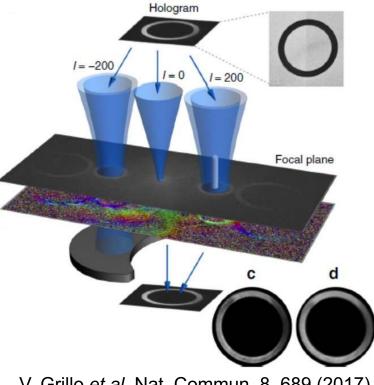
Orbital angular momentum of free electrons



K.Y. Bliokh et al. Physics Reports 690, 1 (2017)



J. Verbeeck et al. Nature 467, 301 (2010)



V. Grillo *et al.* Nat. Commun. 8, 689 (2017) A. Edström *et al.* PRL 116, 127203 (2016)

Helical phase front
Phase singularity on the axis
Orbital angular momentum
Magnetic moment

Inelastic scattering

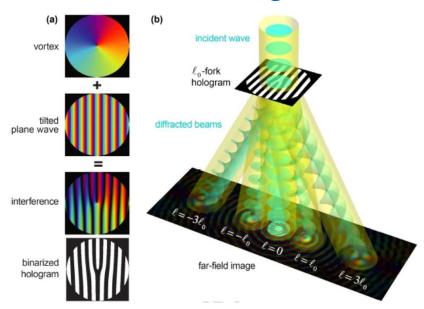
Electron magnetic circular dichroism break symmetry of the p^{\pm} state excitation $l = \pm 1$ (selection rule)

Elastic scattering

Zeeman energy shift
Intensity redistribution
larger OAM, better signal
to noise ratio

How to produce free electron OAM?

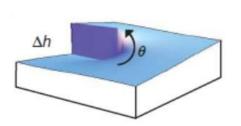
Diffractive hologram



K.Y. Bliokh et al. Physics Reports 690, 1 (2017)

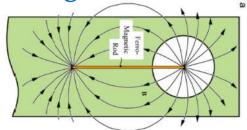
Refractive phase plate

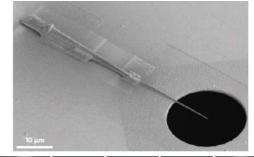
Vortex mask



M. Uchida & A. Tonomura, R. Shiloh *et al.*Nature 464, 737 (2010) Ultramic. 144, 26 (2014)

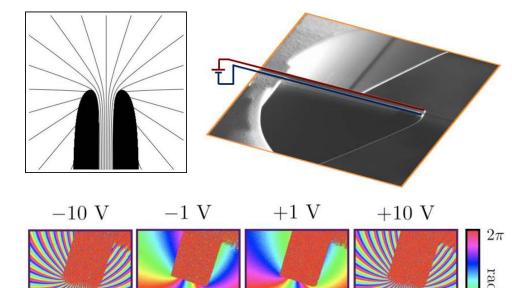
Magnetic needle







Electrostatic chopstick



A. Béché *et al.* Nat. Phys. 10, 26 (2014) G. Pozzi *et al.* Ultramic. 181, 191 (2017) A. M. Blackburn *et al.* Ultramic. 136, 127 (2014) A. Tavabi *et al.* Phys. Rev. Res. 2, 013185 (2020)

- Side lobes and transmission efficiency
- Device obstruction and possibly charging
- OAM mode purity
- Static or dynamic OAM modulation, etc.

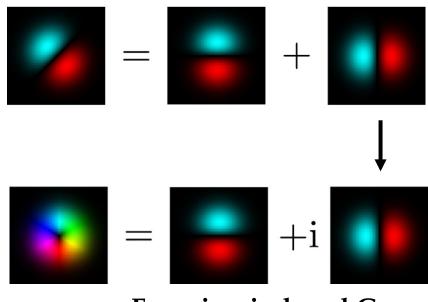


Alternative way: π/2 mode conversion

 HG_{10} HG_{01} **Collaboration:** TU Wien (Peter Schattschneider and his co-workers) **CEOS (Peter Hartel)** FZ Juelich (Penghan Lu and Rafal Dunin-Borkowski) **KIT (Dagmar Gerthen and her co-workers)** $\pi/2$ phase shift LG_{01} M. Beijersbergen et al. Opt. Commun. 96, 123 (1993) C. Kramberger *et al.* Ultramic. 204, 27 (2019) T. Schachinger *et al.* Ultramic. 229, 113340 (2021)

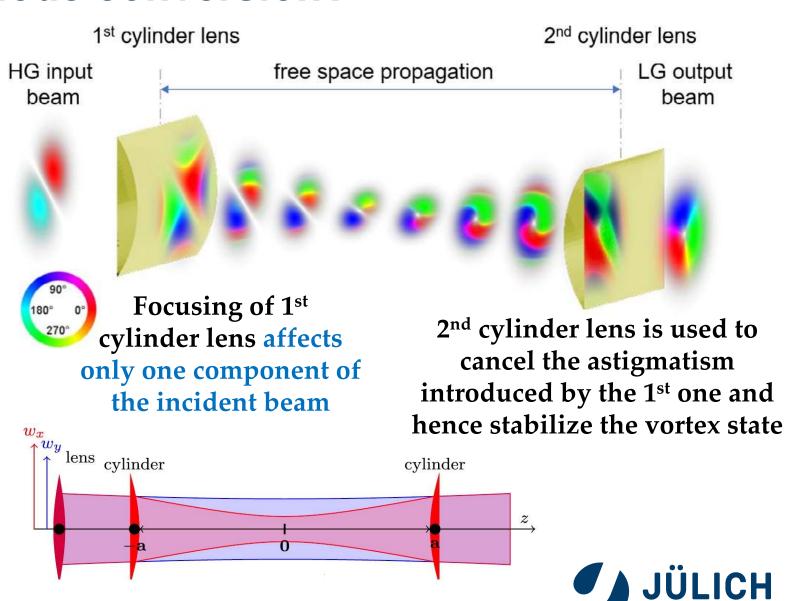
How to achieve $\pi/2$ mode conversion?

HG beam at an angle of 45° with respect to cylinder lens orientation: superposition of 2 orthogonal HG modes



Focusing-induced Gouy phase retardation of $\pi/2$

C. Kramberger *et al.* Ultramic. 204, 27 (2019) T. Schachinger *et al.* Ultramic. 229, 113340 (2021)



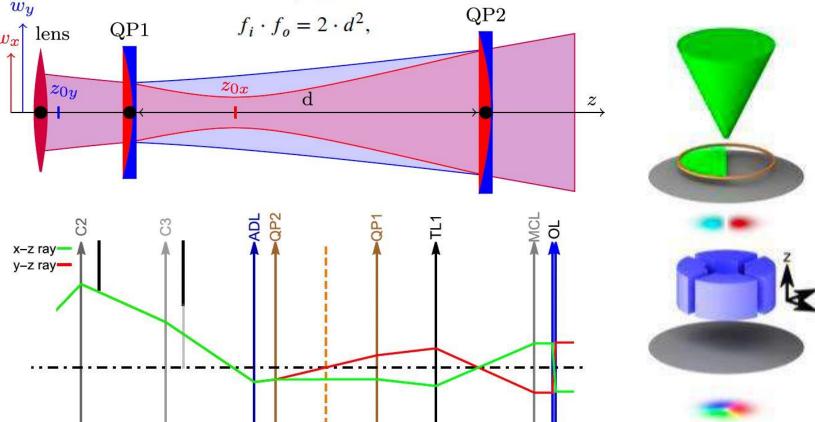
But we don't have cylinder lens in the TEM...

Asymmetric mode conversion

$$w_i = \sqrt{\frac{2f_i}{k}},$$

Instead we used 2 quadrupoles in the CEOS DCOR probe

corrector on Juelich Titan PICO microscope

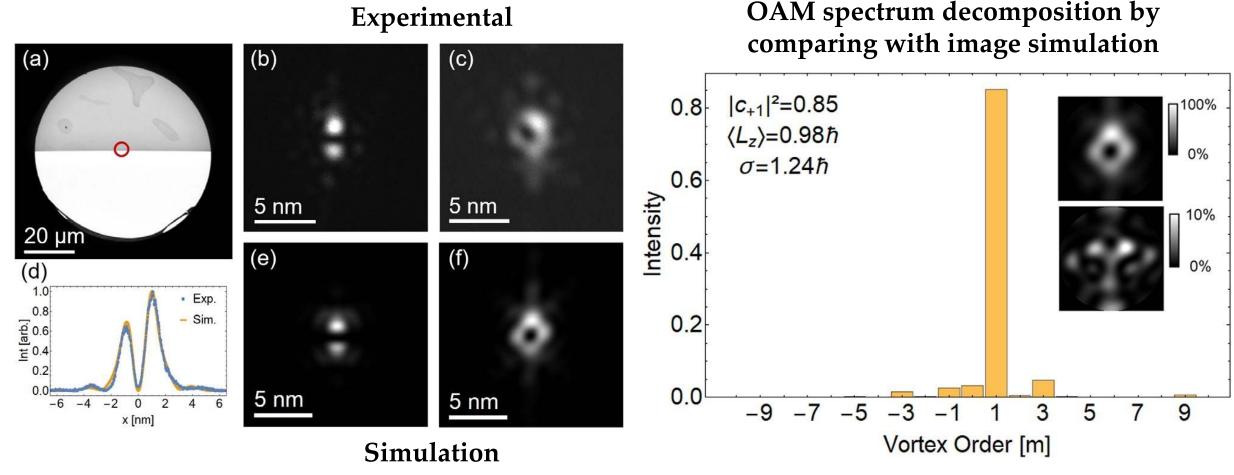




C. Kramberger *et al.* Ultramic. 204, 27 (2019) T. Schachinger *et al.* Ultramic. 229, 113340 (2021)



Experimental demonstration



T. Schachinger et al. Ultramic. 229, 113340 (2021)

Can we measure free electron OAM modes directly as a spectrum like e.g. EELS?



OAM sorter

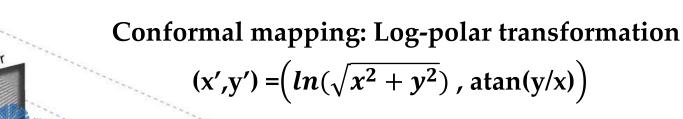
Generator

Collaboration:

CNR (Vincenzo Grillo and his co-workers)

FZ Juelich (Amir Tavabi and others)

TFS (Peter Tiemeijer)

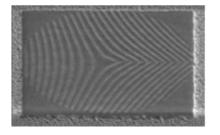


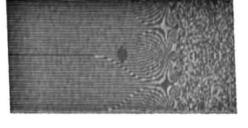
Sorter $(x',y') = \left(\ln(\sqrt{x} + \sqrt{x} +$

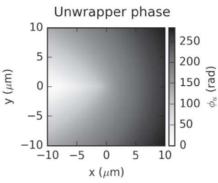
The transformation of coordinates (in geometric optics approximation) transforms a vortex into a plane wave that can be analysed by a diffraction lens

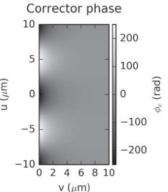
G.C.G. Berkhout *et al.* Phys. Rev. Lett. 105, 153601 (2010) V. Grillo *et al.* Nature Commun. 8, 15536 (2017)

Thin film-based holographic masks





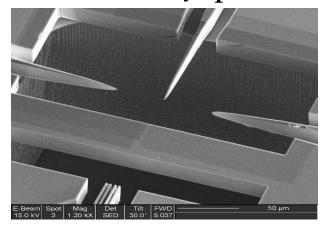


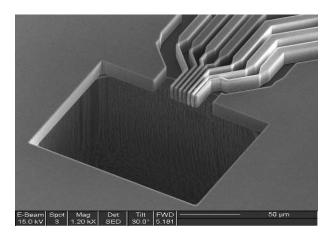




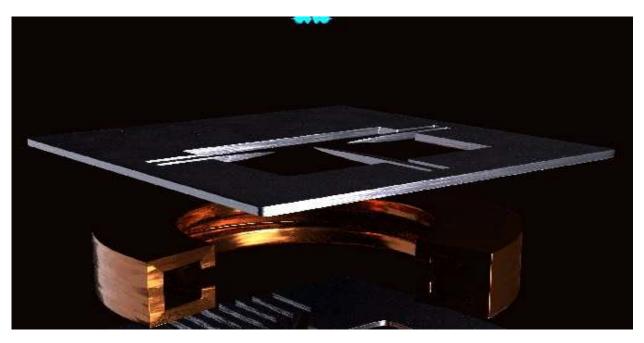
Electrostatic OAM sorter

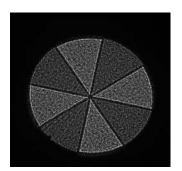
Sorter-1 - OBJ aperture

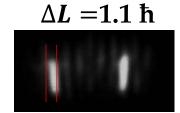


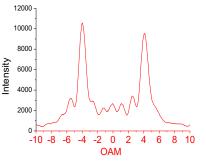


Sorter-2 - SAD aperture









A. Tavabi et al. Phys. Rev. Lett 126, 094802 (2021)



Align sorter devices

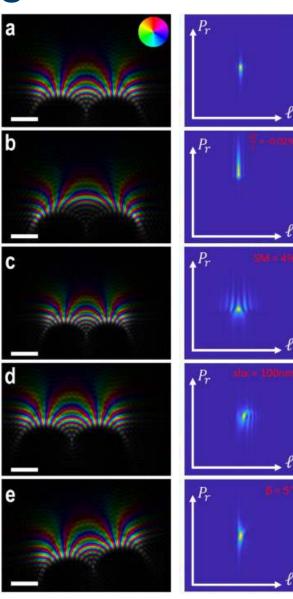
Ideal

Out of focus

Size mismatch

Lateral shift

Rotation



Match between S1 (OBJ) and S2 (SAD)

- image corrector and XL lenses

Image corrector + XL lens combination to change focus

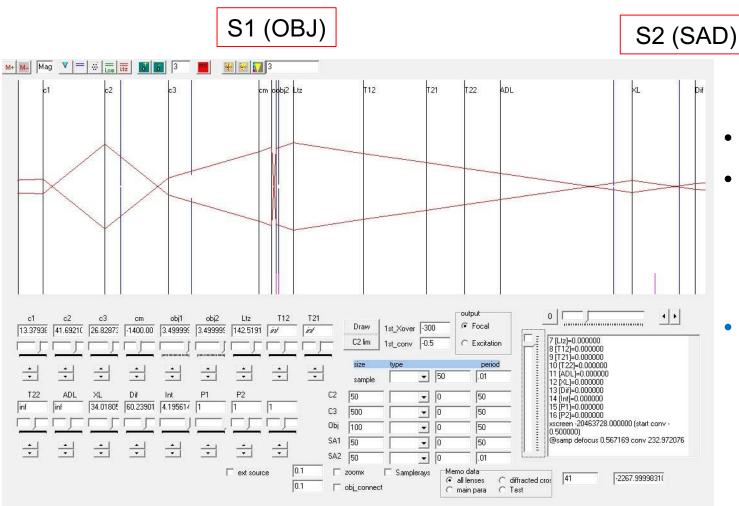
Image corrector + XL lens combination to change size

Deflectors

Image corrector + XL lens combination to change rotation



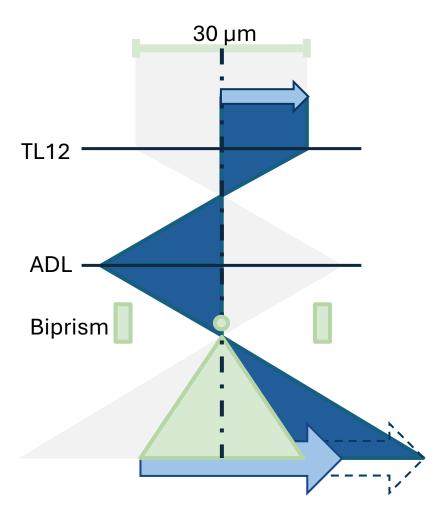
Magnifying S1 image to S2



- Nanofabrication limit to make S2 small
- Tuning the electrostatic field of S1 can help but a large excitation is undesirable because of parasitic large aberration
- Image corrector off (except TL11 and sometimes ADL) and excitation of XL produces an effective long camera length of f =1.4 m



Similar tweaking corrector lens for large FoV holography



Credit: Tolga Wagner (HU Berlin) and Martin Linck (CEOS)

The large field of view holography was achieved by tuning final transfer lenses (TL12, ADL) of image corrector as a demagnifying objective and placing the crossover closer to the biprism plane, thus allowing a wide width of the interference pattern at medium interference fringe spacings.

Alternative setup (developed by myself) in OL-off LM mode reaching (10-40 μ m)² interference FoV.

As an example, a 22µm*22µm FoV holography reconstructed phase image from a phase plate device.

